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Product/Process Change Notification

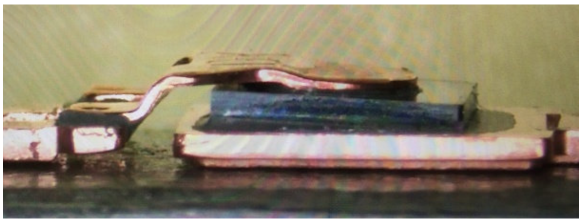
PCN#	Effective Date	Issue Date
2018-04-13C-01	2018/7/13	2018/4/13

PCN Classification	Product Category
Major	TO-277D、TO-277B Package

Subject
Add clip vendor
Affected Product(s)
As attachment
Description of Change(s)
In order to avoid shortage of material, and enhance the speed of delivery, thus, we add a new clip vendor.
Content of Change(s)
Add a new clip vendor
Impact(s)
N/A
Attachment(s)
Reliability Test Report.

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website http://www.secosgmbh.com

Clip Chart	
Original	New
 Top View	 Top View
 Side View	 Side View

Attachment

TO-277D Package	TO-277B Package
SMPD560-C	SMPB6100
SMPD5100-C	SMPB1545L
SMPD5150-C	SMPB15150L
SMPD5200-C	SMPB15100L
SMPD545-C	SMPB05150L
SMPD5200H-C	SMPB05200L
SMPD1045-C	SMPB20100L
SMPD1050-C	SMPB1560L
SMPD1060-C	SMPB10200L
SMPD10150-C	SMPB10100L
SMPD2060-C	SMPB1045L
SMPD10100-C	SMPB1060
SMPD10120-C	SMPB10100
SMPD5100L-C	SMPB5100
SMPD5150L-C	SMPB6100-C
SMPD560L-C	SMPB1545L-C
SMPD1045L-C	SMPB15150L-C
SMPD10100L-C	SMPB15100L-C
SMPD10120L-C	SMPB05150L-C
SMPD10150L-C	SMPB05200L-C
SMPD10200L-C	SMPB20100L-C
SMPD1060L-C	SMPB1560L-C
SMPD1560L-C	SMPB10200L-C
SMPD15100L-C	SMPB10100L-C
SMPD15120L-C	SMPB1045L-C
SMPD15200L-C	SMPB1060-C
SMPD1545L-C	SMPB10100-C
SMPD15150L-C	SMPB5100-C
SMPD2060L-C	
SMPD2045L-C	
SMPD20120L-C	
SMPD20150L-C	
SMPD20200L-C	

SeCoS Corporation

Reliability Testing Summary Report

Date: 2018/04/13 Document No.: SL18-04-D5100

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SMPD5100-C	100 ± 5℃, 80%VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SMPD5100-C	150℃, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SMPD5100-C	121℃, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SMPD5100-C	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SMPD5100-C	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SMPD5100-C	85 ± 2℃, RH=85±5%, 80%VR, 1000 hrs		77	0	0	ACC
Resistance to Solder Heat Test	SMPD5100-C	270℃±5℃, 7Sec +2/-0Sec		77	0	0	ACC

Judgment:

■ **qualified** ☐ **unqualified**

Testing Start Date: 2018.02.12 Testing End Date: 2018.04.13

Tester: King Huang Approval: Peter Yang

High Temperature Reverse Bias Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2018.02.12 ~ 2018.03.27
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	771.4mV	119.6V	0.643uA	792.1mV	118.4V	0.640uA
2	791.5mV	118.6V	0.604uA	781.3mV	120.1V	0.664uA
3	794.2mV	118.9V	0.614uA	782.2mV	120.1V	0.659uA
4	792.1mV	118.2V	0.621uA	791.3mV	118.1V	0.630uA
5	786.3mV	119.9V	0.662uA	785.9mV	119.6V	0.664uA
6	789.6mV	118.1V	0.597uA	783.2mV	118.9V	0.659uA
7	783.6mV	119.9V	0.603uA	791.0mV	118.1V	0.647uA
8	783.8mV	118.6V	0.644uA	786.0mV	119.9V	0.600uA
9	779.0mV	120.4V	0.655uA	785.3mV	119.7V	0.606uA
10	787.2mV	118.6V	0.611uA	789.7mV	118.5V	0.633uA
11	791.0mV	119.0V	0.602uA	795.8mV	119.1V	0.634uA
12	787.9mV	120.4V	0.657uA	781.6mV	118.3V	0.638uA
13	779.5mV	120.2V	0.635uA	776.0mV	119.4V	0.593uA
14	772.6mV	119.6V	0.663uA	771.3mV	120.4V	0.612uA
15	794.5mV	120.4V	0.604uA	791.2mV	118.0V	0.625uA
16	793.7mV	120.3V	0.655uA	773.9mV	120.4V	0.599uA
17	778.4mV	118.1V	0.633uA	781.2mV	118.2V	0.624uA
18	793.7mV	120.2V	0.605uA	772.4mV	118.2V	0.627uA
19	794.2mV	118.2V	0.663uA	792.2mV	120.3V	0.646uA
20	796.1mV	118.9V	0.645uA	785.3mV	120.4V	0.660uA
21	773.2mV	118.8V	0.666uA	778.8mV	119.8V	0.615uA
22	784.4mV	118.4V	0.620uA	788.4mV	119.4V	0.662uA
23	783.2mV	118.0V	0.613uA	778.2mV	120.3V	0.616uA
24	788.4mV	118.3V	0.628uA	793.5mV	118.9V	0.645uA
25	781.9mV	118.7V	0.652uA	779.4mV	118.8V	0.659uA
26	778.5mV	120.3V	0.649uA	786.1mV	120.0V	0.590uA
27	791.6mV	118.6V	0.657uA	777.8mV	120.0V	0.600uA
28	797.0mV	118.8V	0.604uA	793.6mV	120.0V	0.642uA
29	793.7mV	119.2V	0.636uA	793.5mV	119.8V	0.656uA
30	775.1mV	120.0V	0.629uA	782.4mV	119.1V	0.661uA

High Temperature Reverse Bias Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2018.02.12 ~ 2018.03.27
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	789.8mV	120.3V	0.622uA	789.6mV	119.2V	0.656uA
32	777.7mV	118.1V	0.599uA	777.8mV	119.2V	0.658uA
33	780.8mV	118.6V	0.632uA	795.7mV	118.0V	0.628uA
34	778.2mV	119.1V	0.641uA	785.4mV	117.9V	0.622uA
35	774.8mV	118.4V	0.608uA	796.7mV	118.8V	0.601uA
36	774.6mV	119.2V	0.660uA	783.1mV	119.9V	0.598uA
37	774.8mV	120.3V	0.590uA	775.6mV	119.6V	0.596uA
38	775.6mV	119.3V	0.618uA	790.9mV	118.9V	0.662uA
39	792.7mV	118.3V	0.610uA	792.3mV	119.0V	0.595uA
40	773.5mV	118.2V	0.612uA	793.4mV	118.1V	0.610uA
41	779.6mV	118.1V	0.643uA	772.2mV	118.4V	0.629uA
42	794.1mV	119.2V	0.644uA	796.9mV	117.9V	0.598uA
43	794.6mV	120.4V	0.632uA	789.3mV	118.5V	0.650uA
44	777.7mV	119.3V	0.630uA	776.9mV	118.7V	0.633uA
45	788.2mV	118.7V	0.636uA	781.8mV	118.3V	0.647uA
46	785.1mV	120.4V	0.640uA	792.8mV	118.7V	0.645uA
47	777.3mV	120.0V	0.661uA	778.0mV	118.2V	0.653uA
48	775.7mV	119.6V	0.633uA	796.4mV	119.9V	0.629uA
49	794.1mV	118.6V	0.623uA	791.9mV	120.4V	0.655uA
50	780.9mV	119.0V	0.625uA	787.9mV	119.5V	0.641uA
51	789.9mV	118.9V	0.662uA	773.8mV	119.4V	0.653uA
52	782.9mV	120.0V	0.619uA	795.6mV	119.4V	0.614uA
53	775.1mV	118.5V	0.588uA	790.1mV	119.6V	0.639uA
54	784.2mV	118.8V	0.639uA	774.6mV	119.5V	0.599uA
55	777.4mV	118.0V	0.632uA	778.8mV	119.9V	0.618uA
56	782.9mV	120.3V	0.648uA	785.8mV	118.8V	0.605uA
57	773.6mV	118.8V	0.617uA	787.7mV	119.0V	0.604uA
58	782.4mV	119.8V	0.603uA	773.7mV	119.9V	0.599uA
59	796.7mV	119.6V	0.625uA	783.3mV	118.8V	0.615uA
60	791.5mV	119.3V	0.643uA	775.1mV	119.5V	0.620uA

High Temperature Reverse Bias Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2018.02.12 ~ 2018.03.27
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	783.7mV	118.4V	0.656uA	774.8mV	118.1V	0.597uA
62	773.9mV	119.2V	0.622uA	778.2mV	118.1V	0.649uA
63	778.1mV	118.4V	0.642uA	783.6mV	120.3V	0.660uA
64	789.3mV	119.4V	0.591uA	786.6mV	119.0V	0.623uA
65	779.6mV	118.4V	0.650uA	788.3mV	119.7V	0.645uA
66	794.9mV	118.8V	0.654uA	783.9mV	118.2V	0.601uA
67	787.4mV	118.3V	0.599uA	793.7mV	119.4V	0.655uA
68	777.7mV	119.8V	0.643uA	789.7mV	118.0V	0.634uA
69	794.2mV	119.7V	0.636uA	783.1mV	118.4V	0.622uA
70	772.4mV	118.0V	0.641uA	774.7mV	120.0V	0.617uA
71	775.1mV	118.4V	0.590uA	776.1mV	118.2V	0.587uA
72	785.2mV	120.0V	0.596uA	787.3mV	120.3V	0.649uA
73	796.6mV	118.0V	0.655uA	780.4mV	119.3V	0.637uA
74	790.6mV	120.0V	0.665uA	795.1mV	118.4V	0.663uA
75	792.7mV	120.0V	0.654uA	792.2mV	120.2V	0.599uA
76	795.7mV	120.3V	0.602uA	773.2mV	119.6V	0.636uA
77	785.8mV	119.7V	0.626uA	775.0mV	118.5V	0.598uA

Made By: King Huang   Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 150℃, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	789.0mV	118.8V	0.620uA	787.4mV	120.1V	0.587uA
2	780.3mV	119.3V	0.593uA	789.9mV	118.2V	0.594uA
3	795.2mV	119.5V	0.608uA	791.0mV	119.6V	0.659uA
4	780.8mV	117.9V	0.643uA	785.3mV	118.2V	0.590uA
5	793.1mV	120.1V	0.602uA	793.4mV	120.3V	0.606uA
6	779.0mV	119.4V	0.658uA	788.6mV	119.0V	0.609uA
7	773.0mV	120.4V	0.607uA	792.5mV	119.1V	0.639uA
8	795.6mV	120.3V	0.595uA	787.7mV	118.5V	0.658uA
9	781.7mV	120.1V	0.596uA	776.8mV	118.4V	0.636uA
10	779.9mV	120.1V	0.641uA	791.3mV	118.9V	0.647uA
11	771.4mV	118.4V	0.646uA	793.5mV	120.2V	0.652uA
12	776.9mV	119.6V	0.646uA	771.9mV	120.1V	0.602uA
13	790.5mV	120.4V	0.643uA	772.0mV	119.6V	0.637uA
14	772.0mV	119.6V	0.601uA	781.0mV	120.5V	0.602uA
15	796.0mV	118.6V	0.663uA	785.4mV	118.1V	0.643uA
16	774.0mV	118.6V	0.608uA	786.6mV	118.1V	0.595uA
17	775.7mV	119.8V	0.635uA	775.8mV	119.9V	0.623uA
18	782.0mV	119.8V	0.618uA	772.7mV	119.9V	0.597uA
19	774.9mV	119.3V	0.655uA	779.3mV	119.9V	0.652uA
20	776.5mV	118.0V	0.644uA	781.3mV	118.1V	0.624uA
21	783.6mV	118.4V	0.613uA	791.5mV	119.4V	0.592uA
22	783.0mV	118.5V	0.629uA	778.6mV	120.1V	0.643uA
23	792.8mV	118.6V	0.586uA	779.9mV	119.2V	0.662uA
24	793.7mV	118.9V	0.642uA	783.1mV	120.3V	0.655uA
25	786.8mV	118.9V	0.657uA	786.6mV	118.2V	0.661uA
26	784.5mV	119.9V	0.620uA	788.8mV	118.1V	0.660uA
27	788.2mV	120.4V	0.593uA	790.7mV	120.2V	0.639uA
28	790.2mV	119.6V	0.650uA	779.7mV	120.2V	0.611uA
29	780.3mV	118.3V	0.634uA	780.4mV	118.3V	0.658uA
30	793.8mV	120.3V	0.587uA	778.9mV	118.1V	0.589uA

High Temperature Storage Life Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 150℃, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	777.2mV	120.0V	0.660uA	772.8mV	118.1V	0.653uA
32	788.6mV	118.1V	0.651uA	791.7mV	119.9V	0.633uA
33	776.8mV	117.9V	0.643uA	783.2mV	119.9V	0.637uA
34	790.3mV	119.8V	0.636uA	780.6mV	120.1V	0.657uA
35	790.0mV	118.2V	0.660uA	786.9mV	119.3V	0.641uA
36	787.4mV	118.0V	0.641uA	772.5mV	119.8V	0.591uA
37	776.8mV	120.3V	0.608uA	775.7mV	118.7V	0.588uA
38	796.8mV	119.1V	0.652uA	793.5mV	119.9V	0.598uA
39	794.4mV	119.4V	0.663uA	784.2mV	118.0V	0.642uA
40	772.3mV	118.1V	0.656uA	790.8mV	120.3V	0.624uA
41	780.9mV	119.1V	0.612uA	795.4mV	118.4V	0.602uA
42	778.9mV	118.7V	0.651uA	781.9mV	118.1V	0.631uA
43	777.0mV	119.8V	0.602uA	784.4mV	120.2V	0.664uA
44	788.4mV	119.1V	0.607uA	773.2mV	119.3V	0.641uA
45	787.2mV	118.6V	0.631uA	779.3mV	119.8V	0.643uA
46	781.8mV	120.0V	0.606uA	781.1mV	118.4V	0.649uA
47	772.4mV	119.4V	0.651uA	774.2mV	118.6V	0.636uA
48	790.1mV	118.0V	0.593uA	783.7mV	118.7V	0.628uA
49	786.4mV	118.3V	0.660uA	790.2mV	120.3V	0.651uA
50	790.8mV	119.5V	0.620uA	786.4mV	118.4V	0.639uA
51	790.5mV	118.2V	0.613uA	793.3mV	119.3V	0.655uA
52	787.0mV	119.7V	0.587uA	783.1mV	120.1V	0.659uA
53	780.1mV	118.4V	0.629uA	796.7mV	118.8V	0.628uA
54	784.4mV	118.7V	0.654uA	777.7mV	118.1V	0.665uA
55	789.0mV	118.7V	0.666uA	780.4mV	118.9V	0.589uA
56	773.7mV	119.5V	0.589uA	784.8mV	118.6V	0.585uA
57	773.1mV	118.7V	0.658uA	778.0mV	118.3V	0.602uA
58	794.2mV	119.9V	0.666uA	795.0mV	119.3V	0.628uA
59	784.5mV	119.1V	0.656uA	784.3mV	118.7V	0.646uA
60	771.5mV	119.4V	0.598uA	774.8mV	118.6V	0.645uA

High Temperature Storage Life Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 150℃, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	784.1mV	118.3V	0.658uA	773.8mV	118.8V	0.652uA
62	774.3mV	118.0V	0.655uA	788.0mV	118.1V	0.640uA
63	779.1mV	117.9V	0.619uA	784.6mV	118.7V	0.601uA
64	794.1mV	118.8V	0.626uA	785.3mV	119.0V	0.640uA
65	771.9mV	119.8V	0.607uA	772.3mV	119.1V	0.598uA
66	782.4mV	119.8V	0.601uA	772.6mV	118.2V	0.615uA
67	777.8mV	119.4V	0.642uA	795.9mV	118.6V	0.611uA
68	792.5mV	119.1V	0.655uA	794.0mV	120.4V	0.590uA
69	774.0mV	120.4V	0.661uA	794.8mV	118.2V	0.630uA
70	793.5mV	120.3V	0.623uA	784.6mV	118.0V	0.658uA
71	792.5mV	118.7V	0.638uA	774.1mV	118.0V	0.649uA
72	791.8mV	118.6V	0.605uA	780.7mV	120.0V	0.611uA
73	784.3mV	120.1V	0.612uA	783.8mV	118.5V	0.657uA
74	796.5mV	118.5V	0.612uA	775.6mV	120.1V	0.654uA
75	796.2mV	119.7V	0.654uA	787.5mV	119.8V	0.625uA
76	791.6mV	120.4V	0.601uA	776.4mV	119.7V	0.663uA
77	782.6mV	120.4V	0.618uA	777.4mV	118.6V	0.589uA

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2018.02.13 ~ 2018.02.21
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	792.5mV	120.4V	0.648uA	775.7mV	120.1V	0.662uA
2	786.6mV	120.3V	0.633uA	796.1mV	118.2V	0.654uA
3	786.4mV	119.8V	0.647uA	782.2mV	119.0V	0.654uA
4	790.1mV	119.9V	0.644uA	786.5mV	118.9V	0.590uA
5	787.3mV	118.6V	0.597uA	774.3mV	120.5V	0.653uA
6	772.7mV	120.2V	0.664uA	774.5mV	118.8V	0.644uA
7	775.5mV	118.8V	0.617uA	789.9mV	117.9V	0.612uA
8	792.6mV	119.9V	0.666uA	771.8mV	120.4V	0.627uA
9	793.9mV	118.9V	0.658uA	779.8mV	118.2V	0.587uA
10	775.4mV	119.3V	0.619uA	772.8mV	118.4V	0.622uA
11	783.9mV	119.1V	0.662uA	795.7mV	120.0V	0.621uA
12	789.8mV	118.1V	0.634uA	790.1mV	118.7V	0.637uA
13	773.9mV	120.5V	0.644uA	788.8mV	120.1V	0.650uA
14	783.9mV	118.3V	0.608uA	795.8mV	119.3V	0.616uA
15	772.0mV	120.0V	0.659uA	784.5mV	118.1V	0.594uA
16	783.0mV	118.0V	0.607uA	782.2mV	118.6V	0.615uA
17	791.8mV	119.2V	0.606uA	791.4mV	119.7V	0.643uA
18	778.1mV	120.0V	0.591uA	787.0mV	120.0V	0.627uA
19	775.7mV	120.2V	0.637uA	792.9mV	119.1V	0.607uA
20	786.3mV	118.5V	0.590uA	793.7mV	119.4V	0.634uA
21	783.6mV	118.7V	0.655uA	779.2mV	118.4V	0.593uA
22	790.6mV	119.3V	0.586uA	794.7mV	120.2V	0.652uA
23	794.6mV	118.9V	0.643uA	786.0mV	118.6V	0.642uA
24	792.0mV	118.6V	0.598uA	773.7mV	118.3V	0.646uA
25	793.1mV	118.7V	0.650uA	777.6mV	119.3V	0.664uA
26	784.6mV	120.1V	0.628uA	776.5mV	118.9V	0.586uA
27	787.1mV	118.3V	0.664uA	777.3mV	119.6V	0.662uA
28	794.0mV	119.4V	0.623uA	774.2mV	120.3V	0.619uA
29	776.4mV	118.2V	0.662uA	795.3mV	119.5V	0.619uA
30	794.5mV	119.0V	0.590uA	780.2mV	119.2V	0.637uA

SeCoS Corporation

Pressure Cooker Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2018.02.13 ~ 2018.02.21
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	791.8mV	119.6V	0.619uA	782.8mV	119.0V	0.648uA
32	779.4mV	119.1V	0.618uA	785.7mV	120.2V	0.640uA
33	780.4mV	118.7V	0.586uA	796.1mV	120.4V	0.640uA
34	789.6mV	120.1V	0.638uA	784.7mV	119.7V	0.620uA
35	773.2mV	120.4V	0.664uA	771.0mV	120.0V	0.666uA
36	780.2mV	118.1V	0.663uA	794.8mV	119.7V	0.630uA
37	775.1mV	119.6V	0.664uA	790.1mV	120.5V	0.660uA
38	789.8mV	118.5V	0.658uA	774.1mV	119.9V	0.643uA
39	783.2mV	118.4V	0.626uA	792.2mV	118.5V	0.617uA
40	774.2mV	119.1V	0.642uA	780.1mV	120.3V	0.611uA
41	778.5mV	120.4V	0.594uA	774.1mV	119.5V	0.665uA
42	780.7mV	118.2V	0.659uA	791.9mV	119.7V	0.658uA
43	786.4mV	118.8V	0.602uA	789.9mV	117.9V	0.599uA
44	796.1mV	119.1V	0.597uA	774.2mV	118.4V	0.655uA
45	796.9mV	120.5V	0.659uA	786.1mV	119.0V	0.623uA
46	796.0mV	118.3V	0.609uA	780.6mV	119.8V	0.596uA
47	790.9mV	119.4V	0.607uA	792.0mV	119.0V	0.607uA
48	783.0mV	118.9V	0.625uA	775.2mV	119.8V	0.641uA
49	772.5mV	120.5V	0.627uA	787.6mV	118.0V	0.655uA
50	774.9mV	118.6V	0.614uA	779.5mV	118.7V	0.656uA
51	790.5mV	118.4V	0.602uA	785.9mV	118.9V	0.655uA
52	776.3mV	118.2V	0.641uA	791.0mV	120.1V	0.588uA
53	777.8mV	118.7V	0.627uA	776.6mV	119.8V	0.586uA
54	775.6mV	118.7V	0.612uA	792.4mV	118.1V	0.606uA
55	775.1mV	120.1V	0.657uA	785.5mV	118.6V	0.627uA
56	778.8mV	118.5V	0.666uA	773.5mV	118.4V	0.585uA
57	792.6mV	120.2V	0.609uA	791.0mV	119.6V	0.590uA
58	777.8mV	118.6V	0.645uA	793.2mV	119.9V	0.635uA
59	791.7mV	119.5V	0.598uA	794.4mV	119.7V	0.667uA
60	788.5mV	119.9V	0.657uA	772.1mV	118.2V	0.613uA

SeCoS Corporation

Pressure Cooker Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2018.02.13 ~ 2018.02.21
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	790.4mV	120.2V	0.660uA	790.5mV	118.0V	0.622uA
62	792.5mV	118.5V	0.635uA	796.3mV	120.4V	0.613uA
63	795.0mV	120.2V	0.609uA	775.3mV	118.1V	0.605uA
64	793.2mV	119.7V	0.656uA	794.3mV	120.2V	0.646uA
65	789.2mV	120.3V	0.649uA	774.3mV	117.9V	0.640uA
66	782.0mV	119.4V	0.648uA	780.0mV	119.8V	0.650uA
67	796.2mV	120.4V	0.664uA	778.6mV	119.3V	0.641uA
68	777.2mV	117.9V	0.604uA	792.2mV	118.6V	0.643uA
69	785.2mV	118.9V	0.659uA	779.9mV	119.9V	0.599uA
70	785.9mV	120.4V	0.626uA	790.0mV	119.3V	0.590uA
71	778.0mV	119.8V	0.611uA	795.4mV	120.1V	0.633uA
72	781.0mV	118.8V	0.634uA	782.4mV	119.6V	0.652uA
73	782.1mV	119.5V	0.597uA	797.0mV	120.2V	0.615uA
74	792.5mV	120.2V	0.607uA	781.4mV	119.9V	0.648uA
75	787.5mV	119.2V	0.589uA	790.7mV	119.3V	0.586uA
76	776.8mV	118.8V	0.610uA	793.5mV	119.8V	0.630uA
77	795.2mV	118.5V	0.624uA	774.9mV	119.4V	0.607uA

Made By: King Huang　　　　Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2018.02.21 ~ 2018.04.13
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	791.7mV	119.6V	0.610uA	780.8mV	118.7V	0.607uA
2	771.4mV	118.0V	0.651uA	793.9mV	118.4V	0.609uA
3	774.1mV	119.7V	0.615uA	771.7mV	118.6V	0.601uA
4	780.5mV	119.3V	0.637uA	775.9mV	118.9V	0.620uA
5	773.0mV	119.2V	0.628uA	771.9mV	118.2V	0.654uA
6	791.0mV	119.5V	0.640uA	773.5mV	119.1V	0.645uA
7	773.4mV	119.6V	0.585uA	795.0mV	119.8V	0.641uA
8	773.9mV	120.1V	0.622uA	783.0mV	118.3V	0.628uA
9	796.3mV	118.3V	0.647uA	794.9mV	118.8V	0.606uA
10	782.9mV	118.0V	0.597uA	776.2mV	119.4V	0.612uA
11	780.9mV	120.2V	0.627uA	773.0mV	118.5V	0.594uA
12	794.4mV	120.3V	0.615uA	779.8mV	119.3V	0.610uA
13	793.7mV	118.3V	0.658uA	793.3mV	119.7V	0.609uA
14	778.4mV	119.1V	0.615uA	792.2mV	119.6V	0.622uA
15	794.7mV	118.5V	0.665uA	781.3mV	119.7V	0.593uA
16	787.9mV	119.8V	0.602uA	779.5mV	120.3V	0.611uA
17	790.0mV	119.3V	0.629uA	774.5mV	119.2V	0.596uA
18	796.4mV	119.3V	0.663uA	785.0mV	118.4V	0.616uA
19	781.2mV	118.6V	0.596uA	779.9mV	120.3V	0.660uA
20	787.4mV	118.9V	0.629uA	779.7mV	120.4V	0.638uA
21	778.6mV	118.3V	0.595uA	771.4mV	118.4V	0.628uA
22	772.1mV	118.1V	0.590uA	775.4mV	119.7V	0.592uA
23	778.7mV	118.4V	0.609uA	789.7mV	120.0V	0.621uA
24	780.8mV	118.8V	0.663uA	781.7mV	119.0V	0.604uA
25	783.9mV	118.0V	0.619uA	773.4mV	119.0V	0.610uA
26	773.0mV	118.9V	0.586uA	782.6mV	120.0V	0.653uA
27	780.0mV	119.8V	0.649uA	789.4mV	118.3V	0.638uA
28	787.8mV	119.0V	0.666uA	776.8mV	118.3V	0.615uA
29	776.0mV	118.5V	0.664uA	774.3mV	118.6V	0.656uA
30	794.5mV	119.5V	0.591uA	789.5mV	119.0V	0.638uA

Temperature Cycle Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2018.02.21 ~ 2018.04.13
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	789.8mV	118.6V	0.645uA	788.8mV	120.4V	0.629uA
32	778.6mV	118.2V	0.598uA	787.8mV	118.6V	0.627uA
33	786.0mV	119.8V	0.631uA	796.4mV	118.5V	0.622uA
34	789.7mV	118.6V	0.617uA	781.1mV	119.5V	0.651uA
35	793.7mV	119.1V	0.651uA	793.4mV	118.3V	0.617uA
36	774.7mV	119.1V	0.628uA	772.8mV	118.2V	0.598uA
37	789.4mV	118.2V	0.634uA	789.1mV	120.4V	0.602uA
38	785.9mV	118.8V	0.588uA	771.8mV	120.5V	0.616uA
39	788.1mV	120.3V	0.603uA	771.2mV	119.5V	0.614uA
40	790.7mV	119.4V	0.625uA	774.2mV	120.2V	0.604uA
41	774.2mV	120.0V	0.587uA	796.8mV	118.4V	0.642uA
42	778.6mV	120.0V	0.596uA	795.9mV	118.3V	0.633uA
43	779.3mV	119.3V	0.664uA	787.2mV	119.6V	0.597uA
44	788.2mV	118.1V	0.618uA	792.0mV	119.6V	0.598uA
45	771.7mV	119.6V	0.607uA	776.4mV	118.1V	0.615uA
46	792.7mV	119.0V	0.616uA	773.9mV	119.8V	0.643uA
47	795.2mV	119.0V	0.593uA	776.6mV	119.8V	0.623uA
48	775.0mV	118.6V	0.626uA	778.7mV	118.6V	0.632uA
49	794.4mV	118.7V	0.666uA	778.1mV	119.6V	0.661uA
50	789.5mV	119.0V	0.625uA	784.2mV	119.3V	0.595uA
51	786.0mV	119.2V	0.650uA	784.9mV	120.3V	0.662uA
52	787.1mV	119.9V	0.617uA	780.9mV	118.7V	0.622uA
53	773.5mV	119.8V	0.649uA	771.7mV	119.3V	0.633uA
54	779.9mV	119.8V	0.625uA	793.8mV	118.4V	0.619uA
55	795.8mV	120.1V	0.638uA	778.7mV	119.9V	0.632uA
56	783.6mV	119.5V	0.658uA	790.4mV	119.3V	0.591uA
57	794.6mV	120.0V	0.657uA	796.9mV	120.5V	0.647uA
58	785.9mV	118.6V	0.630uA	794.4mV	119.6V	0.610uA
59	771.7mV	119.9V	0.595uA	795.2mV	119.2V	0.662uA
60	784.1mV	119.8V	0.613uA	786.5mV	117.9V	0.599uA

SeCoS Corporation

Temperature Cycle Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2018.02.21 ~ 2018.04.13
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	793.4mV	118.8V	0.586uA	779.1mV	120.3V	0.597uA
62	776.0mV	120.2V	0.645uA	772.0mV	119.6V	0.658uA
63	771.1mV	117.9V	0.613uA	791.2mV	118.5V	0.656uA
64	784.1mV	119.3V	0.665uA	778.8mV	118.0V	0.616uA
65	773.4mV	119.3V	0.621uA	780.7mV	118.2V	0.593uA
66	784.2mV	118.4V	0.605uA	777.6mV	119.6V	0.653uA
67	771.2mV	120.0V	0.593uA	796.7mV	118.6V	0.648uA
68	797.0mV	119.7V	0.640uA	778.4mV	120.0V	0.657uA
69	771.2mV	119.1V	0.650uA	792.2mV	118.5V	0.640uA
70	786.7mV	119.3V	0.595uA	772.2mV	119.8V	0.663uA
71	773.2mV	119.0V	0.633uA	778.3mV	118.7V	0.620uA
72	776.9mV	119.4V	0.663uA	775.8mV	118.9V	0.592uA
73	795.1mV	118.0V	0.601uA	777.8mV	118.1V	0.615uA
74	782.0mV	119.0V	0.620uA	777.3mV	117.9V	0.648uA
75	793.4mV	118.6V	0.595uA	786.0mV	118.6V	0.665uA
76	792.4mV	118.2V	0.634uA	783.2mV	119.7V	0.610uA
77	787.5mV	120.4V	0.636uA	790.8mV	119.4V	0.635uA

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	775.9mV	120.3V	0.632uA	790.8mV	118.7V	0.644uA
2	775.6mV	119.9V	0.592uA	796.6mV	119.2V	0.616uA
3	787.5mV	120.1V	0.643uA	782.5mV	120.3V	0.608uA
4	775.0mV	118.7V	0.600uA	785.1mV	118.7V	0.588uA
5	779.0mV	118.2V	0.604uA	778.4mV	119.2V	0.620uA
6	788.3mV	119.3V	0.585uA	772.0mV	118.4V	0.642uA
7	776.9mV	118.9V	0.640uA	796.2mV	118.0V	0.610uA
8	772.3mV	118.1V	0.647uA	789.4mV	119.6V	0.593uA
9	793.7mV	119.0V	0.606uA	772.5mV	119.5V	0.615uA
10	783.9mV	119.1V	0.665uA	777.0mV	119.7V	0.653uA
11	776.6mV	118.7V	0.658uA	788.1mV	117.9V	0.617uA
12	790.1mV	118.0V	0.650uA	788.2mV	119.0V	0.600uA
13	786.5mV	119.0V	0.593uA	781.9mV	119.7V	0.646uA
14	793.6mV	118.8V	0.641uA	794.1mV	119.8V	0.597uA
15	772.8mV	120.1V	0.617uA	783.0mV	119.8V	0.650uA
16	795.3mV	117.9V	0.597uA	783.5mV	120.0V	0.588uA
17	775.3mV	119.5V	0.664uA	787.6mV	118.2V	0.627uA
18	776.8mV	119.8V	0.625uA	789.7mV	119.3V	0.665uA
19	782.3mV	119.9V	0.665uA	784.0mV	119.6V	0.614uA
20	793.2mV	119.8V	0.619uA	774.0mV	118.6V	0.646uA
21	786.7mV	119.6V	0.630uA	771.3mV	120.4V	0.632uA
22	784.6mV	118.7V	0.660uA	793.8mV	119.1V	0.591uA
23	792.8mV	120.0V	0.592uA	778.2mV	120.4V	0.635uA
24	794.2mV	119.8V	0.651uA	780.2mV	119.7V	0.627uA
25	791.2mV	120.1V	0.619uA	782.0mV	119.0V	0.613uA
26	795.1mV	119.8V	0.667uA	778.9mV	120.5V	0.586uA
27	796.2mV	119.3V	0.589uA	772.3mV	119.9V	0.623uA
28	776.6mV	119.6V	0.630uA	779.8mV	119.4V	0.594uA
29	791.5mV	118.7V	0.640uA	796.0mV	119.3V	0.596uA
30	790.5mV	118.0V	0.638uA	775.4mV	118.1V	0.655uA

High Temperature High Humidity Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	782.0mV	118.1V	0.619uA	780.4mV	118.7V	0.605uA
32	783.8mV	119.6V	0.621uA	795.6mV	118.3V	0.650uA
33	774.7mV	118.1V	0.652uA	775.2mV	118.6V	0.594uA
34	781.0mV	118.0V	0.602uA	793.7mV	118.7V	0.636uA
35	779.9mV	119.7V	0.659uA	771.0mV	119.5V	0.621uA
36	790.2mV	119.5V	0.649uA	785.6mV	120.0V	0.665uA
37	794.7mV	120.5V	0.656uA	781.9mV	119.7V	0.603uA
38	777.4mV	119.0V	0.635uA	780.6mV	119.6V	0.631uA
39	782.0mV	118.8V	0.652uA	785.2mV	118.5V	0.601uA
40	795.0mV	120.2V	0.666uA	779.0mV	119.3V	0.612uA
41	785.8mV	118.9V	0.663uA	795.8mV	119.6V	0.591uA
42	789.3mV	118.6V	0.637uA	796.5mV	120.3V	0.642uA
43	771.6mV	120.4V	0.620uA	777.1mV	119.7V	0.588uA
44	774.5mV	119.5V	0.639uA	776.8mV	120.3V	0.617uA
45	790.8mV	118.3V	0.623uA	792.4mV	119.7V	0.634uA
46	792.0mV	117.9V	0.614uA	781.7mV	119.2V	0.610uA
47	782.6mV	120.3V	0.604uA	778.5mV	118.2V	0.621uA
48	796.5mV	117.9V	0.587uA	792.3mV	120.5V	0.647uA
49	788.2mV	119.2V	0.657uA	778.5mV	120.2V	0.644uA
50	780.3mV	118.7V	0.618uA	783.9mV	118.5V	0.650uA
51	781.3mV	118.5V	0.655uA	774.9mV	118.3V	0.591uA
52	778.2mV	118.3V	0.663uA	793.6mV	118.2V	0.593uA
53	790.9mV	118.7V	0.608uA	772.2mV	120.1V	0.624uA
54	784.7mV	119.4V	0.615uA	777.5mV	118.0V	0.607uA
55	793.6mV	120.1V	0.594uA	783.1mV	118.3V	0.651uA
56	795.1mV	117.9V	0.611uA	775.8mV	118.1V	0.616uA
57	773.6mV	119.2V	0.622uA	781.9mV	120.0V	0.664uA
58	796.4mV	119.7V	0.657uA	778.2mV	118.6V	0.647uA
59	778.7mV	117.9V	0.644uA	783.7mV	119.8V	0.648uA
60	796.3mV	118.1V	0.637uA	771.3mV	120.0V	0.603uA

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	790.6mV	119.7V	0.611uA	795.0mV	118.9V	0.598uA
62	796.0mV	119.2V	0.640uA	793.5mV	119.5V	0.641uA
63	785.1mV	118.9V	0.622uA	783.3mV	118.0V	0.595uA
64	787.1mV	119.4V	0.617uA	795.6mV	120.2V	0.589uA
65	776.2mV	117.9V	0.612uA	790.8mV	120.4V	0.656uA
66	772.0mV	120.5V	0.617uA	793.5mV	118.8V	0.650uA
67	792.4mV	118.2V	0.594uA	777.9mV	118.0V	0.609uA
68	787.8mV	119.9V	0.646uA	775.7mV	118.2V	0.607uA
69	794.7mV	119.6V	0.651uA	774.6mV	118.8V	0.603uA
70	773.4mV	118.6V	0.652uA	786.2mV	120.4V	0.628uA
71	775.4mV	119.9V	0.659uA	778.6mV	119.3V	0.621uA
72	783.4mV	120.3V	0.642uA	788.1mV	120.5V	0.657uA
73	785.7mV	119.4V	0.649uA	784.8mV	118.7V	0.628uA
74	771.2mV	118.2V	0.619uA	796.6mV	119.3V	0.600uA
75	787.1mV	118.9V	0.602uA	777.3mV	118.9V	0.599uA
76	771.2mV	118.7V	0.652uA	791.1mV	118.2V	0.586uA
77	774.9mV	118.8V	0.589uA	794.2mV	119.9V	0.657uA

Made By: King Huang Approval: Peter Yang

High Temper High Humidity Reverse Bies Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2018.02.27 ~ 2018.04.12
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	795.1mV	119.3V	0.630uA	790.5mV	119.1V	0.592uA
2	789.7mV	118.0V	0.637uA	791.4mV	119.9V	0.633uA
3	793.4mV	118.5V	0.600uA	788.9mV	118.5V	0.640uA
4	785.5mV	120.4V	0.656uA	777.8mV	119.8V	0.648uA
5	794.7mV	118.4V	0.609uA	775.4mV	119.0V	0.666uA
6	786.3mV	118.8V	0.639uA	780.9mV	120.1V	0.636uA
7	787.6mV	120.2V	0.598uA	792.0mV	119.4V	0.657uA
8	793.8mV	119.3V	0.618uA	796.6mV	118.9V	0.665uA
9	796.5mV	119.7V	0.636uA	782.7mV	119.0V	0.603uA
10	791.6mV	117.9V	0.663uA	786.5mV	118.3V	0.591uA
11	772.7mV	118.6V	0.604uA	790.3mV	119.5V	0.656uA
12	774.0mV	119.3V	0.661uA	788.3mV	120.1V	0.626uA
13	771.1mV	118.6V	0.665uA	776.0mV	118.4V	0.615uA
14	792.7mV	117.9V	0.661uA	778.0mV	118.5V	0.660uA
15	791.0mV	118.1V	0.600uA	781.4mV	118.7V	0.643uA
16	792.0mV	118.0V	0.590uA	789.1mV	118.6V	0.607uA
17	790.3mV	120.0V	0.596uA	780.3mV	118.3V	0.590uA
18	781.5mV	119.3V	0.627uA	775.8mV	118.7V	0.604uA
19	773.8mV	118.5V	0.622uA	778.7mV	118.5V	0.589uA
20	776.8mV	119.0V	0.655uA	792.1mV	119.2V	0.600uA
21	782.6mV	119.0V	0.625uA	773.9mV	118.6V	0.597uA
22	771.9mV	119.6V	0.594uA	774.0mV	119.8V	0.617uA
23	794.0mV	120.4V	0.599uA	776.1mV	118.9V	0.662uA
24	773.2mV	118.8V	0.606uA	785.9mV	119.5V	0.620uA
25	783.5mV	119.5V	0.613uA	794.9mV	119.5V	0.598uA
26	784.8mV	118.4V	0.652uA	791.3mV	119.4V	0.616uA
27	775.4mV	119.2V	0.591uA	789.2mV	119.9V	0.601uA
28	782.2mV	119.6V	0.627uA	771.8mV	118.7V	0.659uA
29	778.1mV	119.5V	0.646uA	782.7mV	118.1V	0.659uA
30	790.1mV	118.4V	0.621uA	774.5mV	119.2V	0.587uA

High Temper High Humidity Reverse Bies Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2018.02.27 ~ 2018.04.12
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	774.8mV	119.1V	0.661uA	790.8mV	119.7V	0.631uA
32	773.4mV	119.3V	0.600uA	773.3mV	120.3V	0.597uA
33	779.1mV	118.4V	0.604uA	784.6mV	118.8V	0.660uA
34	771.9mV	119.8V	0.667uA	792.0mV	119.9V	0.606uA
35	777.8mV	118.1V	0.604uA	788.2mV	119.1V	0.602uA
36	785.2mV	119.4V	0.613uA	773.7mV	119.3V	0.650uA
37	783.8mV	119.6V	0.635uA	773.9mV	119.8V	0.639uA
38	786.4mV	118.9V	0.659uA	771.9mV	119.6V	0.661uA
39	786.9mV	118.8V	0.586uA	773.6mV	120.4V	0.619uA
40	789.4mV	119.1V	0.639uA	784.5mV	120.4V	0.626uA
41	782.7mV	119.5V	0.663uA	780.1mV	118.2V	0.585uA
42	782.0mV	119.8V	0.659uA	789.2mV	120.2V	0.654uA
43	772.8mV	119.5V	0.635uA	793.2mV	120.4V	0.639uA
44	777.1mV	119.1V	0.607uA	791.3mV	118.5V	0.637uA
45	785.4mV	118.9V	0.605uA	772.6mV	120.5V	0.586uA
46	796.1mV	119.8V	0.652uA	777.0mV	118.7V	0.617uA
47	784.3mV	118.9V	0.618uA	779.0mV	119.0V	0.596uA
48	776.5mV	118.3V	0.615uA	795.9mV	120.3V	0.589uA
49	793.4mV	120.4V	0.590uA	783.5mV	119.4V	0.611uA
50	788.6mV	118.0V	0.596uA	796.0mV	118.8V	0.665uA
51	786.9mV	119.7V	0.592uA	796.5mV	120.4V	0.590uA
52	779.2mV	118.8V	0.629uA	790.7mV	117.9V	0.638uA
53	795.8mV	118.0V	0.603uA	779.7mV	119.7V	0.588uA
54	776.6mV	118.0V	0.641uA	779.4mV	119.7V	0.647uA
55	773.2mV	119.4V	0.591uA	775.8mV	119.3V	0.600uA
56	792.5mV	120.1V	0.592uA	778.6mV	119.8V	0.593uA
57	775.7mV	118.7V	0.600uA	784.9mV	120.2V	0.634uA
58	782.8mV	120.1V	0.601uA	774.6mV	119.0V	0.663uA
59	791.5mV	118.0V	0.655uA	772.9mV	118.7V	0.650uA
60	786.0mV	118.8V	0.641uA	795.2mV	118.8V	0.650uA

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High Temper High Humidity Reverse Bies Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2018.02.27 ~ 2018.04.12
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	773.9mV	118.9V	0.654uA	790.8mV	118.8V	0.612uA
62	777.2mV	118.0V	0.638uA	773.1mV	118.4V	0.655uA
63	793.4mV	119.6V	0.653uA	792.9mV	118.1V	0.635uA
64	773.9mV	120.4V	0.640uA	778.1mV	119.0V	0.612uA
65	794.5mV	118.3V	0.665uA	773.3mV	118.6V	0.643uA
66	775.6mV	119.0V	0.665uA	786.8mV	117.9V	0.662uA
67	783.4mV	118.4V	0.660uA	787.9mV	118.2V	0.640uA
68	791.0mV	119.0V	0.662uA	793.6mV	120.4V	0.663uA
69	795.6mV	117.9V	0.586uA	790.1mV	118.2V	0.623uA
70	786.2mV	119.6V	0.631uA	772.7mV	120.1V	0.645uA
71	781.5mV	118.1V	0.626uA	783.6mV	119.7V	0.647uA
72	781.4mV	120.4V	0.591uA	787.4mV	119.2V	0.631uA
73	790.1mV	120.3V	0.609uA	771.2mV	119.0V	0.650uA
74	787.6mV	119.6V	0.604uA	795.5mV	118.6V	0.649uA
75	782.4mV	118.9V	0.662uA	788.8mV	118.2V	0.627uA
76	784.8mV	120.4V	0.585uA	787.7mV	120.2V	0.589uA
77	774.5mV	118.1V	0.623uA	777.1mV	117.9V	0.598uA

Made By: King Huang　　　　Approval: Peter Yang

SeCoS Corporation

Resistance to Solder Heat Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 270℃ ± 5℃, 7Sec + 2Sec/-0Sec
Test Date: 2018.04.13
Test Standard : JESD22 STANDARD Method-B106
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	791.0mV	119.7V	0.646uA	777.8mV	119.4V	0.655uA
2	787.2mV	119.2V	0.661uA	773.0mV	120.3V	0.614uA
3	795.7mV	117.9V	0.598uA	781.6mV	118.5V	0.606uA
4	772.7mV	119.8V	0.632uA	793.5mV	118.4V	0.657uA
5	781.2mV	117.9V	0.609uA	780.8mV	118.5V	0.648uA
6	787.3mV	119.3V	0.615uA	785.1mV	119.9V	0.624uA
7	772.0mV	118.5V	0.637uA	774.1mV	120.4V	0.605uA
8	777.6mV	120.4V	0.664uA	789.0mV	118.6V	0.597uA
9	790.6mV	119.0V	0.601uA	774.1mV	118.3V	0.634uA
10	787.1mV	117.9V	0.609uA	793.5mV	119.0V	0.634uA
11	795.4mV	119.2V	0.657uA	772.2mV	118.6V	0.638uA
12	782.6mV	119.5V	0.656uA	795.2mV	119.0V	0.589uA
13	773.1mV	118.0V	0.586uA	783.3mV	119.3V	0.603uA
14	775.1mV	118.4V	0.592uA	783.7mV	119.2V	0.656uA
15	777.6mV	119.1V	0.613uA	774.3mV	119.1V	0.650uA
16	795.7mV	118.7V	0.664uA	774.6mV	118.4V	0.594uA
17	784.7mV	118.8V	0.645uA	791.5mV	119.5V	0.606uA
18	787.3mV	120.3V	0.606uA	772.8mV	119.5V	0.615uA
19	771.8mV	118.6V	0.599uA	775.3mV	118.2V	0.646uA
20	782.8mV	118.9V	0.655uA	776.4mV	118.9V	0.665uA
21	781.1mV	118.5V	0.599uA	783.9mV	119.0V	0.663uA
22	782.8mV	118.3V	0.611uA	782.4mV	120.5V	0.589uA
23	773.8mV	119.8V	0.601uA	783.0mV	119.3V	0.663uA
24	794.7mV	119.3V	0.619uA	777.3mV	119.0V	0.606uA
25	782.6mV	118.4V	0.644uA	772.2mV	118.9V	0.608uA
26	783.0mV	120.3V	0.642uA	784.7mV	118.3V	0.601uA
27	790.1mV	118.4V	0.624uA	771.1mV	120.0V	0.602uA
28	781.5mV	120.4V	0.642uA	771.5mV	118.6V	0.600uA
29	792.8mV	119.5V	0.657uA	785.6mV	119.4V	0.664uA
30	792.4mV	118.3V	0.622uA	781.6mV	118.8V	0.591uA

Resistance to Solder Heat Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 270℃ ± 5℃, 7Sec + 2Sec/-0Sec
Test Date: 2018.04.13
Test Standard : JESD22 STANDARD Method-B106
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	796.2mV	120.2V	0.612uA	794.6mV	118.7V	0.616uA
32	774.9mV	119.1V	0.654uA	780.0mV	118.1V	0.629uA
33	778.7mV	120.0V	0.641uA	782.9mV	119.0V	0.634uA
34	792.0mV	120.5V	0.664uA	776.2mV	118.1V	0.602uA
35	787.9mV	120.3V	0.620uA	781.8mV	118.9V	0.620uA
36	771.2mV	119.2V	0.592uA	771.8mV	120.2V	0.633uA
37	795.0mV	119.2V	0.660uA	779.2mV	118.3V	0.597uA
38	782.4mV	119.7V	0.611uA	789.6mV	118.7V	0.628uA
39	775.9mV	120.1V	0.662uA	777.7mV	119.3V	0.611uA
40	782.6mV	120.5V	0.602uA	777.1mV	119.7V	0.604uA
41	783.8mV	119.4V	0.618uA	785.0mV	119.5V	0.592uA
42	782.2mV	119.4V	0.619uA	784.1mV	118.0V	0.643uA
43	776.9mV	119.7V	0.608uA	794.8mV	120.2V	0.649uA
44	773.9mV	118.6V	0.639uA	792.7mV	119.3V	0.665uA
45	778.9mV	118.6V	0.652uA	788.9mV	120.1V	0.599uA
46	773.4mV	119.0V	0.589uA	778.4mV	118.9V	0.620uA
47	794.8mV	120.0V	0.603uA	791.6mV	118.7V	0.642uA
48	790.3mV	118.1V	0.586uA	781.2mV	119.7V	0.657uA
49	794.0mV	119.5V	0.633uA	788.5mV	118.5V	0.593uA
50	779.6mV	118.3V	0.633uA	776.1mV	119.4V	0.637uA
51	772.1mV	120.4V	0.590uA	791.2mV	118.8V	0.606uA
52	783.7mV	119.1V	0.621uA	791.3mV	120.0V	0.632uA
53	771.8mV	120.4V	0.620uA	783.5mV	120.3V	0.609uA
54	791.6mV	118.4V	0.599uA	788.5mV	118.3V	0.634uA
55	789.2mV	120.4V	0.617uA	785.5mV	120.3V	0.664uA
56	791.2mV	119.2V	0.623uA	785.2mV	120.0V	0.664uA
57	792.3mV	118.3V	0.667uA	795.0mV	117.9V	0.632uA
58	784.1mV	120.2V	0.592uA	793.3mV	118.6V	0.636uA
59	786.4mV	120.1V	0.642uA	780.4mV	119.7V	0.588uA
60	773.3mV	119.1V	0.590uA	794.5mV	120.3V	0.663uA

SeCoS Corporation

Resistance to Solder Heat Test Data

Report No : T180413-D5100
Part No : SMPD5100-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<820mV@IF=5A, VB>100V@IR=1mA, IR<300uA@VR=100V
Test Condition: 270℃ ± 5℃, 7Sec + 2Sec/-0Sec
Test Date: 2018.04.13
Test Standard : JESD22 STANDARD Method-B106
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	780.3mV	118.4V	0.621uA	784.1mV	119.2V	0.654uA
62	774.7mV	119.8V	0.652uA	775.6mV	120.5V	0.616uA
63	793.1mV	118.7V	0.648uA	792.6mV	120.0V	0.596uA
64	771.7mV	119.6V	0.610uA	784.6mV	117.9V	0.603uA
65	786.1mV	118.2V	0.641uA	788.7mV	118.8V	0.620uA
66	791.5mV	118.8V	0.652uA	788.5mV	119.8V	0.597uA
67	795.7mV	118.8V	0.637uA	779.5mV	118.5V	0.657uA
68	796.8mV	119.1V	0.587uA	796.1mV	118.1V	0.649uA
69	790.3mV	118.6V	0.585uA	772.8mV	119.2V	0.610uA
70	785.5mV	120.1V	0.656uA	795.2mV	119.4V	0.621uA
71	781.7mV	119.8V	0.640uA	794.1mV	119.7V	0.622uA
72	786.6mV	119.2V	0.653uA	794.8mV	117.9V	0.662uA
73	789.0mV	119.6V	0.641uA	786.6mV	118.1V	0.589uA
74	779.3mV	120.4V	0.587uA	790.5mV	119.2V	0.626uA
75	789.1mV	119.2V	0.586uA	790.5mV	120.3V	0.664uA
76	793.8mV	118.5V	0.651uA	781.7mV	118.1V	0.665uA
77	791.3mV	118.6V	0.613uA	791.4mV	118.7V	0.603uA

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Reliability Testing Summary Report

Date: 2018/04/13 Document No.: SL18-04-B10100L

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SMPB10100L-C	100℃ ± 5℃, 80%VR, T = 1000 hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SMPB10100L-C	150℃, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SMPB10100L-C	121℃, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SMPB10100L-C	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SMPB10100L-C	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SMPB10100L-C	85 ± 2℃, RH=85±5%, 80%VR, 1000 hrs		77	0	0	ACC
Resistance to Solder Heat Test	SMPB10100L-C	270℃±5℃, 7Sec +2/-0Sec		77	0	0	ACC

Judgment:

■ **qualified** ☐ **unqualified**

Testing Start Date: 2018.02.12 Testing End Date: 2018.04.13

Tester: King Huang Approval: Peter Yang

High Temperature Reverse Bias Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2018.02.12 ~ 2018.03.27
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	630.9mV	117.0V	11.87uA	634.8mV	116.2V	12.73uA
2	632.4mV	116.7V	11.33uA	635.1mV	116.7V	12.02uA
3	639.5mV	117.7V	15.12uA	633.8mV	115.4V	11.28uA
4	630.8mV	116.6V	12.62uA	632.6mV	117.7V	13.04uA
5	632.7mV	115.6V	14.73uA	639.7mV	117.8V	13.54uA
6	636.0mV	117.5V	13.80uA	630.3mV	116.6V	12.76uA
7	638.8mV	116.3V	14.81uA	630.7mV	118.8V	10.97uA
8	625.2mV	117.3V	11.67uA	630.9mV	118.7V	14.95uA
9	628.9mV	118.6V	14.01uA	632.0mV	117.3V	15.24uA
10	635.8mV	116.7V	11.80uA	625.3mV	118.1V	15.03uA
11	631.9mV	115.6V	13.07uA	632.5mV	118.5V	10.95uA
12	628.1mV	115.3V	10.77uA	633.2mV	116.6V	13.06uA
13	630.5mV	118.6V	10.99uA	625.7mV	117.9V	14.12uA
14	627.8mV	117.7V	14.96uA	630.9mV	118.3V	13.42uA
15	638.6mV	116.8V	11.44uA	636.3mV	118.8V	12.42uA
16	628.6mV	116.2V	13.36uA	630.0mV	116.7V	13.13uA
17	636.1mV	116.9V	13.33uA	639.2mV	117.7V	11.15uA
18	630.9mV	118.7V	11.81uA	628.1mV	116.4V	13.62uA
19	631.0mV	117.5V	13.70uA	631.7mV	118.7V	15.16uA
20	634.9mV	117.2V	11.85uA	635.3mV	117.1V	12.82uA
21	629.3mV	115.5V	12.80uA	639.8mV	117.1V	13.21uA
22	638.1mV	117.2V	12.36uA	636.1mV	115.3V	13.84uA
23	636.5mV	118.3V	12.74uA	631.9mV	117.0V	13.43uA
24	629.9mV	116.5V	13.77uA	635.0mV	117.3V	15.26uA
25	627.0mV	115.6V	12.42uA	632.6mV	117.7V	12.51uA
26	629.1mV	118.0V	13.33uA	627.6mV	116.1V	14.64uA
27	627.0mV	117.9V	13.40uA	636.6mV	117.1V	12.14uA
28	634.0mV	118.2V	12.32uA	634.2mV	116.9V	13.31uA
29	639.8mV	117.3V	12.81uA	638.2mV	116.4V	13.77uA
30	639.3mV	117.8V	11.14uA	634.2mV	115.2V	12.48uA

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2018.02.12 ~ 2018.03.27
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	626.5mV	115.4V	13.73uA	636.1mV	116.6V	11.04uA
32	634.4mV	116.5V	15.01uA	634.3mV	115.9V	11.30uA
33	635.0mV	117.8V	14.45uA	638.7mV	118.0V	13.24uA
34	637.4mV	115.9V	14.01uA	635.2mV	118.6V	11.93uA
35	631.6mV	118.3V	11.79uA	626.4mV	116.0V	14.76uA
36	626.0mV	116.2V	14.64uA	636.7mV	116.2V	12.57uA
37	633.1mV	116.2V	11.05uA	635.5mV	118.6V	13.46uA
38	626.8mV	117.6V	11.07uA	628.4mV	116.7V	14.29uA
39	630.2mV	115.2V	13.61uA	638.5mV	115.6V	11.87uA
40	625.1mV	117.9V	13.43uA	631.5mV	118.8V	11.90uA
41	632.5mV	118.5V	12.43uA	634.8mV	116.3V	14.91uA
42	635.5mV	116.9V	14.47uA	632.4mV	117.1V	11.23uA
43	630.2mV	117.6V	13.15uA	630.5mV	117.9V	12.06uA
44	637.6mV	117.1V	15.00uA	636.1mV	118.2V	11.75uA
45	628.3mV	117.6V	11.05uA	632.3mV	115.4V	13.50uA
46	638.3mV	118.1V	12.58uA	638.5mV	115.5V	12.12uA
47	635.8mV	117.8V	15.22uA	630.2mV	118.3V	11.34uA
48	639.7mV	118.8V	11.11uA	631.5mV	116.0V	14.67uA
49	631.1mV	118.3V	11.25uA	626.5mV	118.7V	14.05uA
50	625.1mV	118.6V	14.43uA	638.4mV	117.2V	13.88uA
51	634.9mV	116.5V	15.09uA	630.2mV	117.9V	12.56uA
52	629.4mV	117.6V	13.81uA	627.0mV	116.8V	12.99uA
53	639.7mV	116.0V	10.96uA	637.9mV	117.1V	11.56uA
54	630.4mV	116.0V	12.70uA	630.5mV	116.8V	13.11uA
55	635.0mV	116.9V	14.39uA	629.9mV	116.3V	12.04uA
56	634.0mV	116.2V	13.84uA	633.7mV	118.5V	14.68uA
57	633.2mV	118.1V	11.70uA	636.6mV	116.0V	12.52uA
58	630.6mV	118.1V	14.90uA	637.8mV	118.1V	13.12uA
59	629.0mV	117.2V	12.09uA	638.3mV	115.9V	15.04uA
60	629.2mV	116.6V	11.70uA	639.1mV	116.9V	14.58uA

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2018.02.12 ~ 2018.03.27
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	636.9mV	117.7V	10.98uA	625.5mV	116.5V	15.26uA
62	635.9mV	116.6V	13.56uA	637.4mV	117.2V	12.82uA
63	625.2mV	118.7V	13.12uA	631.7mV	117.7V	15.19uA
64	628.6mV	115.3V	13.85uA	629.6mV	118.5V	11.61uA
65	625.9mV	117.8V	12.87uA	628.2mV	115.9V	11.60uA
66	634.0mV	116.1V	11.19uA	626.8mV	118.6V	14.67uA
67	634.8mV	118.2V	13.05uA	635.5mV	117.7V	13.61uA
68	639.4mV	118.4V	14.06uA	628.7mV	116.8V	12.88uA
69	636.9mV	117.8V	11.83uA	629.4mV	118.2V	11.28uA
70	637.9mV	117.8V	13.64uA	633.3mV	116.6V	14.52uA
71	626.8mV	118.2V	12.71uA	634.8mV	116.2V	11.25uA
72	630.9mV	117.9V	12.20uA	634.7mV	116.6V	13.36uA
73	635.3mV	118.1V	14.67uA	636.7mV	116.4V	11.09uA
74	629.6mV	117.4V	15.21uA	638.3mV	118.1V	11.72uA
75	633.7mV	116.3V	11.65uA	638.4mV	116.6V	12.74uA
76	629.7mV	117.7V	14.01uA	626.0mV	118.2V	14.02uA
77	627.2mV	116.3V	11.17uA	634.1mV	116.7V	14.50uA

Made By: King Huang　　　　Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 150℃, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	636.7mV	117.4V	13.26uA	634.5mV	118.6V	12.03uA
2	634.1mV	118.6V	11.09uA	625.6mV	117.2V	13.19uA
3	634.9mV	118.0V	11.36uA	630.4mV	117.9V	14.52uA
4	633.6mV	115.5V	12.30uA	639.7mV	117.4V	14.30uA
5	627.7mV	117.6V	12.56uA	627.4mV	117.8V	10.97uA
6	628.2mV	116.7V	14.79uA	636.5mV	118.1V	13.67uA
7	632.7mV	118.4V	10.84uA	627.9mV	116.7V	14.30uA
8	630.7mV	116.0V	15.24uA	636.0mV	115.8V	11.86uA
9	632.2mV	116.3V	13.48uA	635.4mV	117.6V	11.33uA
10	637.2mV	115.7V	12.25uA	632.6mV	115.6V	12.72uA
11	639.8mV	116.2V	10.97uA	633.5mV	116.9V	13.15uA
12	638.0mV	116.2V	14.52uA	634.0mV	118.3V	12.80uA
13	632.4mV	117.3V	14.08uA	634.9mV	118.8V	13.38uA
14	629.4mV	118.3V	13.20uA	635.4mV	116.7V	13.32uA
15	626.7mV	118.0V	12.37uA	635.8mV	116.5V	10.98uA
16	638.8mV	118.7V	14.25uA	635.5mV	116.5V	13.71uA
17	628.5mV	117.7V	11.19uA	628.5mV	117.7V	11.88uA
18	631.9mV	118.0V	11.53uA	635.5mV	118.5V	13.59uA
19	629.3mV	117.0V	14.20uA	631.1mV	115.6V	13.96uA
20	626.0mV	115.5V	14.35uA	638.3mV	117.9V	13.57uA
21	629.0mV	115.2V	11.09uA	627.0mV	118.8V	11.89uA
22	631.4mV	118.5V	13.80uA	638.7mV	116.6V	12.86uA
23	639.4mV	117.8V	11.49uA	630.8mV	117.1V	12.64uA
24	626.6mV	118.7V	11.62uA	632.5mV	115.6V	13.25uA
25	636.1mV	118.5V	11.98uA	639.2mV	117.7V	12.12uA
26	628.2mV	116.6V	14.85uA	631.6mV	118.2V	13.54uA
27	639.5mV	116.2V	13.65uA	625.0mV	116.2V	12.57uA
28	636.4mV	118.6V	11.52uA	630.7mV	115.4V	10.94uA
29	639.0mV	118.6V	13.08uA	632.1mV	116.1V	14.50uA
30	630.4mV	117.6V	14.88uA	631.1mV	116.8V	13.09uA

High Temperature Storage Life Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 150℃, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	627.2mV	116.7V	14.07uA	631.9mV	117.4V	11.76uA
32	631.8mV	115.6V	12.87uA	629.3mV	116.7V	14.10uA
33	633.9mV	118.2V	13.16uA	637.9mV	116.6V	11.58uA
34	631.1mV	115.5V	13.78uA	638.2mV	117.2V	12.72uA
35	631.8mV	116.9V	13.97uA	636.9mV	116.4V	12.13uA
36	627.7mV	116.6V	13.75uA	631.4mV	115.7V	14.02uA
37	634.4mV	117.3V	12.46uA	634.9mV	118.4V	14.59uA
38	633.0mV	117.1V	14.38uA	630.4mV	116.3V	14.53uA
39	638.5mV	115.4V	10.88uA	635.3mV	118.0V	13.87uA
40	638.9mV	117.6V	14.60uA	628.7mV	117.9V	11.63uA
41	630.9mV	118.4V	11.47uA	639.7mV	117.5V	13.01uA
42	625.2mV	116.2V	11.63uA	625.9mV	117.4V	11.52uA
43	626.4mV	117.6V	11.88uA	630.4mV	115.4V	12.33uA
44	631.7mV	116.2V	13.45uA	627.1mV	118.8V	14.03uA
45	633.0mV	117.4V	14.66uA	636.7mV	117.1V	15.29uA
46	633.4mV	117.1V	12.79uA	625.8mV	116.6V	11.14uA
47	627.1mV	118.0V	13.67uA	636.9mV	115.3V	12.91uA
48	636.5mV	118.4V	12.10uA	637.6mV	117.2V	14.83uA
49	631.3mV	118.0V	13.61uA	637.7mV	116.4V	10.94uA
50	634.8mV	118.5V	12.54uA	629.4mV	117.1V	12.72uA
51	629.0mV	115.8V	13.08uA	629.4mV	116.7V	15.01uA
52	634.3mV	115.2V	12.29uA	634.6mV	118.4V	13.27uA
53	629.8mV	116.4V	13.05uA	635.6mV	117.4V	13.24uA
54	639.9mV	115.8V	12.45uA	628.4mV	118.6V	14.99uA
55	630.5mV	117.2V	13.32uA	625.4mV	118.2V	14.35uA
56	634.1mV	116.9V	15.03uA	631.6mV	116.0V	12.15uA
57	639.7mV	115.2V	13.08uA	635.3mV	118.0V	14.45uA
58	639.5mV	118.1V	10.73uA	639.5mV	116.7V	10.87uA
59	638.9mV	118.5V	15.10uA	632.2mV	115.3V	11.41uA
60	627.9mV	116.5V	13.97uA	636.4mV	117.5V	12.98uA

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 150℃, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	629.8mV	118.5V	13.95uA	627.9mV	117.6V	11.00uA
62	630.1mV	117.7V	10.71uA	635.7mV	117.1V	11.17uA
63	631.7mV	116.5V	15.03uA	626.8mV	115.2V	13.21uA
64	632.3mV	115.9V	13.57uA	630.5mV	117.6V	11.42uA
65	630.2mV	116.8V	11.76uA	637.3mV	117.3V	11.02uA
66	638.2mV	117.8V	13.96uA	635.6mV	117.1V	14.42uA
67	635.9mV	118.0V	12.89uA	628.2mV	118.7V	13.51uA
68	630.0mV	117.8V	12.80uA	637.3mV	118.1V	15.13uA
69	628.0mV	117.2V	14.23uA	637.3mV	118.4V	15.20uA
70	639.6mV	117.1V	11.94uA	635.1mV	118.4V	12.20uA
71	633.6mV	118.0V	10.86uA	634.4mV	118.6V	14.26uA
72	638.0mV	115.5V	12.36uA	630.5mV	117.8V	12.36uA
73	630.9mV	116.0V	13.52uA	626.8mV	117.6V	14.77uA
74	638.7mV	115.9V	11.30uA	629.4mV	116.8V	14.43uA
75	627.4mV	118.2V	13.40uA	633.3mV	117.1V	11.99uA
76	636.6mV	117.8V	13.46uA	632.9mV	115.4V	13.61uA
77	625.2mV	117.5V	13.26uA	629.4mV	115.6V	12.38uA

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2018.02.13 ~ 2018.02.21
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	628.1mV	117.8V	13.89uA	637.6mV	117.8V	11.92uA
2	632.6mV	118.3V	12.15uA	626.8mV	117.4V	11.64uA
3	635.4mV	117.2V	15.13uA	630.7mV	117.4V	10.78uA
4	637.7mV	117.6V	14.99uA	629.6mV	118.7V	11.85uA
5	627.3mV	117.1V	11.98uA	634.8mV	117.1V	13.76uA
6	630.6mV	117.7V	12.56uA	630.6mV	115.5V	11.76uA
7	639.2mV	117.7V	14.22uA	636.7mV	117.2V	12.33uA
8	631.7mV	117.0V	14.18uA	625.6mV	116.9V	13.86uA
9	628.4mV	117.7V	10.73uA	626.7mV	116.3V	13.47uA
10	637.4mV	118.1V	13.13uA	627.0mV	118.3V	14.31uA
11	629.7mV	117.3V	12.33uA	637.3mV	117.5V	13.62uA
12	633.5mV	118.7V	13.31uA	625.8mV	115.8V	10.98uA
13	631.8mV	117.7V	14.86uA	626.5mV	117.7V	14.09uA
14	625.3mV	118.0V	12.50uA	630.8mV	118.3V	11.13uA
15	631.7mV	115.9V	11.34uA	634.8mV	116.8V	14.56uA
16	627.1mV	118.4V	13.09uA	627.0mV	115.8V	14.87uA
17	634.5mV	117.9V	13.49uA	634.1mV	118.2V	12.05uA
18	638.6mV	118.1V	13.63uA	639.6mV	116.9V	13.06uA
19	637.1mV	115.9V	12.73uA	638.3mV	116.4V	14.92uA
20	627.1mV	116.3V	11.22uA	638.4mV	118.4V	11.91uA
21	629.3mV	115.3V	12.07uA	636.9mV	118.0V	11.88uA
22	633.0mV	115.5V	13.78uA	629.1mV	118.0V	12.10uA
23	636.1mV	115.7V	12.10uA	628.8mV	117.7V	11.31uA
24	638.4mV	115.7V	11.76uA	628.7mV	116.9V	13.44uA
25	639.5mV	115.7V	11.35uA	629.6mV	117.6V	13.25uA
26	638.9mV	118.5V	13.69uA	635.7mV	116.4V	13.46uA
27	634.5mV	115.7V	13.63uA	635.2mV	118.4V	14.06uA
28	629.6mV	118.0V	13.75uA	631.2mV	115.3V	12.07uA
29	628.0mV	115.8V	15.28uA	631.1mV	115.8V	12.81uA
30	626.0mV	118.7V	12.84uA	631.1mV	115.9V	13.52uA

SeCoS Corporation

Pressure Cooker Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2018.02.13 ~ 2018.02.21
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	630.4mV	115.2V	12.28uA	632.5mV	118.4V	11.31uA
32	629.9mV	115.3V	11.90uA	634.0mV	116.8V	10.85uA
33	628.3mV	116.8V	13.11uA	625.4mV	116.6V	13.82uA
34	631.5mV	118.5V	13.59uA	628.1mV	116.1V	12.41uA
35	634.6mV	116.5V	14.67uA	626.8mV	117.3V	12.26uA
36	639.9mV	116.0V	11.29uA	636.7mV	115.3V	13.36uA
37	629.4mV	116.3V	14.62uA	630.6mV	116.9V	11.13uA
38	630.5mV	118.1V	12.01uA	638.2mV	115.2V	11.65uA
39	637.6mV	116.9V	14.60uA	630.3mV	116.7V	11.48uA
40	625.1mV	115.7V	12.46uA	632.7mV	118.3V	10.99uA
41	633.1mV	117.5V	12.36uA	626.2mV	118.0V	11.24uA
42	627.3mV	117.4V	14.87uA	629.8mV	117.0V	14.06uA
43	628.2mV	118.6V	14.53uA	628.6mV	115.4V	11.01uA
44	625.8mV	118.5V	12.37uA	626.5mV	118.1V	15.21uA
45	629.4mV	117.7V	14.83uA	628.5mV	117.5V	14.51uA
46	630.6mV	116.4V	13.43uA	634.1mV	115.5V	11.02uA
47	627.4mV	115.7V	14.02uA	633.8mV	118.6V	12.75uA
48	632.9mV	116.4V	12.08uA	638.0mV	115.3V	11.64uA
49	628.8mV	117.0V	11.09uA	629.9mV	117.8V	15.26uA
50	626.6mV	116.7V	12.08uA	626.5mV	117.4V	11.92uA
51	627.2mV	117.8V	11.85uA	636.2mV	115.3V	12.90uA
52	639.6mV	116.0V	12.34uA	630.3mV	117.3V	11.01uA
53	638.5mV	115.5V	13.65uA	627.0mV	118.5V	11.70uA
54	628.4mV	115.8V	11.85uA	637.8mV	116.3V	13.55uA
55	631.2mV	118.6V	11.79uA	639.9mV	116.6V	14.97uA
56	628.9mV	118.4V	12.41uA	630.8mV	116.0V	11.32uA
57	637.7mV	115.7V	11.09uA	639.9mV	115.5V	13.86uA
58	637.0mV	115.4V	14.37uA	625.8mV	118.1V	13.44uA
59	634.4mV	115.7V	15.07uA	636.6mV	117.3V	12.01uA
60	625.7mV	115.5V	13.25uA	626.3mV	117.4V	14.49uA

SeCoS Corporation

Pressure Cooker Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2018.02.13 ~ 2018.02.21
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	632.3mV	115.9V	12.41uA	632.9mV	115.9V	12.38uA
62	634.8mV	117.4V	15.05uA	634.6mV	118.8V	11.07uA
63	638.3mV	116.7V	13.35uA	628.3mV	116.0V	13.23uA
64	638.5mV	117.5V	12.61uA	630.9mV	118.5V	12.59uA
65	638.5mV	116.1V	11.84uA	635.0mV	116.2V	12.99uA
66	638.1mV	117.0V	14.41uA	631.1mV	118.7V	15.11uA
67	633.1mV	116.0V	10.73uA	631.6mV	116.0V	12.43uA
68	638.9mV	118.7V	11.70uA	630.0mV	118.5V	12.30uA
69	633.7mV	115.4V	10.88uA	637.2mV	117.0V	13.58uA
70	628.3mV	116.1V	14.91uA	638.4mV	115.5V	13.05uA
71	630.0mV	116.4V	11.82uA	630.6mV	117.5V	14.82uA
72	629.2mV	116.7V	12.75uA	634.0mV	117.0V	12.38uA
73	627.6mV	117.5V	13.66uA	637.8mV	117.0V	11.39uA
74	628.0mV	115.8V	11.92uA	636.8mV	117.2V	12.28uA
75	635.9mV	118.1V	13.01uA	638.5mV	118.4V	11.05uA
76	632.2mV	118.7V	12.75uA	626.0mV	118.8V	14.25uA
77	639.3mV	117.7V	11.88uA	633.0mV	117.7V	12.03uA

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2018.02.21 ~ 2018.04.13
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	634.6mV	115.7V	10.97uA	637.4mV	117.0V	13.40uA
2	639.6mV	117.4V	10.87uA	633.0mV	115.9V	12.95uA
3	631.1mV	118.1V	10.67uA	631.0mV	118.6V	14.01uA
4	630.1mV	117.5V	10.88uA	638.6mV	117.5V	14.11uA
5	631.4mV	116.9V	13.53uA	634.9mV	118.7V	14.36uA
6	631.3mV	116.7V	12.69uA	635.9mV	116.6V	13.46uA
7	625.9mV	117.6V	11.37uA	631.1mV	117.7V	13.20uA
8	626.6mV	115.6V	13.67uA	634.3mV	117.4V	12.89uA
9	629.3mV	116.3V	15.07uA	636.8mV	116.2V	14.13uA
10	632.0mV	117.5V	13.13uA	627.2mV	117.4V	14.96uA
11	631.0mV	117.1V	13.09uA	629.7mV	118.3V	12.91uA
12	628.1mV	116.5V	11.62uA	631.6mV	116.2V	11.81uA
13	629.0mV	117.8V	13.15uA	625.0mV	116.4V	15.15uA
14	634.4mV	116.9V	12.31uA	636.9mV	116.3V	13.14uA
15	629.8mV	116.1V	14.44uA	631.6mV	118.6V	14.64uA
16	636.9mV	117.1V	11.35uA	635.4mV	116.3V	13.39uA
17	631.8mV	115.8V	12.28uA	633.6mV	115.9V	13.93uA
18	627.3mV	115.5V	12.17uA	631.5mV	115.4V	10.87uA
19	628.9mV	118.4V	15.26uA	634.2mV	115.4V	10.86uA
20	633.5mV	118.7V	15.14uA	626.3mV	115.7V	12.64uA
21	627.8mV	118.7V	11.53uA	632.5mV	116.6V	12.04uA
22	626.5mV	118.2V	11.95uA	630.7mV	117.5V	12.66uA
23	632.3mV	115.5V	11.11uA	630.7mV	117.3V	12.08uA
24	628.7mV	118.1V	12.33uA	638.8mV	117.4V	12.18uA
25	639.0mV	116.7V	14.11uA	634.3mV	115.6V	11.85uA
26	638.9mV	117.8V	11.31uA	639.4mV	116.4V	11.24uA
27	630.4mV	116.1V	12.72uA	626.2mV	115.4V	11.73uA
28	629.7mV	116.4V	12.19uA	630.9mV	116.1V	14.77uA
29	632.0mV	117.8V	10.70uA	639.8mV	115.3V	12.50uA
30	635.9mV	115.5V	11.11uA	631.7mV	116.3V	11.82uA

Temperature Cycle Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2018.02.21 ~ 2018.04.13
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	626.8mV	118.0V	12.13uA	635.6mV	116.7V	10.84uA
32	634.0mV	118.1V	14.51uA	638.6mV	115.5V	11.25uA
33	635.4mV	115.7V	11.06uA	633.5mV	118.5V	15.25uA
34	634.7mV	116.0V	11.54uA	628.1mV	115.8V	10.76uA
35	628.4mV	116.4V	14.65uA	629.8mV	115.4V	14.07uA
36	634.0mV	117.8V	11.07uA	625.2mV	118.7V	10.95uA
37	635.8mV	116.1V	14.09uA	636.3mV	116.6V	11.01uA
38	628.0mV	115.4V	10.90uA	637.9mV	116.0V	14.38uA
39	631.0mV	117.1V	14.40uA	630.0mV	116.7V	11.86uA
40	629.5mV	115.8V	11.81uA	628.2mV	116.9V	14.00uA
41	629.9mV	118.3V	12.53uA	627.1mV	115.5V	14.61uA
42	631.2mV	117.7V	15.22uA	627.5mV	115.6V	13.78uA
43	627.9mV	118.5V	13.89uA	636.7mV	115.3V	10.98uA
44	634.3mV	117.9V	13.77uA	629.4mV	117.4V	13.34uA
45	629.0mV	117.9V	14.34uA	631.8mV	115.9V	12.88uA
46	635.7mV	116.2V	12.27uA	628.3mV	118.2V	11.19uA
47	633.5mV	118.2V	14.31uA	632.0mV	118.1V	12.55uA
48	636.3mV	116.1V	13.92uA	637.4mV	118.2V	10.89uA
49	636.5mV	116.7V	13.57uA	631.3mV	115.9V	12.14uA
50	636.5mV	117.5V	14.60uA	638.1mV	117.5V	13.38uA
51	636.8mV	115.6V	14.57uA	635.7mV	115.5V	13.23uA
52	637.4mV	115.9V	13.36uA	627.2mV	116.8V	15.15uA
53	628.4mV	118.7V	12.77uA	631.2mV	117.3V	12.12uA
54	631.2mV	118.2V	12.01uA	625.4mV	117.6V	13.80uA
55	637.1mV	116.3V	12.77uA	630.6mV	117.4V	13.52uA
56	628.9mV	118.7V	11.04uA	638.7mV	117.7V	12.94uA
57	629.0mV	115.4V	14.65uA	631.9mV	117.4V	11.17uA
58	632.5mV	118.6V	13.71uA	627.1mV	117.9V	15.10uA
59	636.5mV	115.7V	15.28uA	634.4mV	117.1V	14.73uA
60	633.8mV	117.4V	14.17uA	626.4mV	116.7V	11.37uA

SeCoS Corporation

Temperature Cycle Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2018.02.21 ~ 2018.04.13
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	636.4mV	116.4V	14.28uA	631.3mV	115.8V	11.91uA
62	634.0mV	115.9V	13.84uA	635.6mV	117.5V	11.76uA
63	638.8mV	117.1V	13.43uA	633.8mV	118.1V	14.98uA
64	632.6mV	116.1V	12.52uA	630.3mV	115.7V	14.03uA
65	626.8mV	118.3V	13.26uA	625.1mV	116.1V	13.62uA
66	631.8mV	117.5V	10.86uA	636.3mV	116.6V	15.08uA
67	638.2mV	115.9V	12.97uA	636.5mV	118.1V	14.04uA
68	630.4mV	117.2V	13.67uA	629.2mV	117.0V	15.04uA
69	634.0mV	117.0V	14.05uA	633.8mV	115.9V	12.74uA
70	638.9mV	117.1V	13.34uA	630.6mV	117.8V	12.91uA
71	628.6mV	116.3V	13.83uA	638.0mV	117.2V	11.09uA
72	639.1mV	115.9V	13.62uA	638.5mV	116.1V	12.58uA
73	639.3mV	117.8V	12.41uA	639.8mV	118.2V	15.27uA
74	632.5mV	117.1V	13.71uA	634.1mV	117.1V	14.99uA
75	631.6mV	118.1V	12.83uA	634.5mV	117.5V	10.91uA
76	630.1mV	117.9V	11.08uA	625.5mV	118.2V	14.86uA
77	627.2mV	116.9V	13.05uA	631.0mV	115.8V	11.46uA

Made By: King Huang

Approval: Peter Yang

High Temperature High Humidity Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	634.5mV	117.3V	14.00uA	632.6mV	115.5V	14.01uA
2	630.1mV	116.7V	14.23uA	631.9mV	117.6V	14.50uA
3	628.2mV	115.4V	12.00uA	638.6mV	117.4V	14.73uA
4	628.9mV	115.6V	13.05uA	628.5mV	118.7V	12.89uA
5	635.1mV	118.8V	13.26uA	628.1mV	115.6V	14.33uA
6	626.7mV	117.4V	11.47uA	626.9mV	118.7V	14.71uA
7	628.5mV	115.8V	11.02uA	638.0mV	116.5V	13.09uA
8	626.9mV	117.7V	15.28uA	633.1mV	115.8V	11.59uA
9	639.5mV	117.9V	13.75uA	637.0mV	116.0V	14.48uA
10	627.1mV	117.2V	14.16uA	628.1mV	116.0V	11.72uA
11	636.1mV	116.7V	11.97uA	635.6mV	117.3V	14.97uA
12	628.5mV	118.0V	14.07uA	625.7mV	115.6V	13.29uA
13	638.2mV	117.4V	13.93uA	628.2mV	118.1V	10.72uA
14	639.1mV	117.8V	14.57uA	627.7mV	117.9V	13.85uA
15	627.1mV	117.1V	14.61uA	639.4mV	117.7V	12.09uA
16	626.3mV	117.6V	11.61uA	628.6mV	117.5V	13.18uA
17	634.7mV	117.3V	13.21uA	627.5mV	118.4V	12.40uA
18	638.0mV	117.2V	14.82uA	631.0mV	116.1V	14.25uA
19	627.5mV	116.3V	13.28uA	631.0mV	115.6V	13.18uA
20	634.2mV	115.6V	14.40uA	638.1mV	116.6V	14.59uA
21	634.8mV	117.0V	13.05uA	630.7mV	117.6V	14.53uA
22	636.0mV	117.1V	13.39uA	635.6mV	118.0V	11.46uA
23	634.9mV	115.4V	11.74uA	628.3mV	116.6V	14.39uA
24	636.2mV	115.8V	12.12uA	639.2mV	117.9V	14.91uA
25	631.7mV	116.5V	11.87uA	638.7mV	116.8V	13.56uA
26	638.8mV	116.2V	11.43uA	628.3mV	116.4V	11.55uA
27	628.7mV	118.7V	14.17uA	637.4mV	116.1V	13.49uA
28	627.1mV	117.6V	12.48uA	629.5mV	116.1V	11.97uA
29	637.3mV	116.0V	11.67uA	639.8mV	117.8V	12.50uA
30	626.8mV	117.3V	11.65uA	631.2mV	118.2V	14.39uA

High Temperature High Humidity Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	629.6mV	117.0V	11.22uA	635.8mV	116.1V	14.89uA
32	635.5mV	115.9V	12.25uA	635.5mV	117.9V	14.92uA
33	638.1mV	115.3V	11.59uA	637.1mV	117.0V	11.62uA
34	629.9mV	118.7V	11.04uA	633.7mV	118.6V	12.28uA
35	630.6mV	116.9V	10.85uA	633.2mV	116.7V	11.00uA
36	638.4mV	115.5V	13.30uA	626.2mV	115.3V	15.12uA
37	639.1mV	118.0V	14.56uA	637.7mV	116.0V	12.80uA
38	636.3mV	115.2V	11.66uA	626.4mV	118.4V	12.77uA
39	625.4mV	118.0V	11.31uA	639.4mV	118.1V	10.69uA
40	639.5mV	118.7V	10.75uA	634.3mV	116.3V	11.21uA
41	630.4mV	117.8V	14.22uA	628.7mV	116.9V	13.21uA
42	629.0mV	117.4V	12.80uA	628.3mV	117.5V	14.98uA
43	628.7mV	116.7V	10.94uA	626.0mV	118.2V	12.41uA
44	635.9mV	115.4V	14.59uA	634.4mV	117.6V	12.31uA
45	625.0mV	117.8V	13.29uA	637.5mV	116.6V	11.81uA
46	633.3mV	117.2V	11.06uA	635.2mV	115.6V	11.19uA
47	631.0mV	118.6V	11.69uA	626.0mV	116.6V	12.11uA
48	629.9mV	115.6V	13.41uA	630.6mV	116.8V	12.24uA
49	634.4mV	118.4V	13.73uA	634.9mV	118.3V	11.41uA
50	638.0mV	116.9V	12.29uA	631.5mV	116.8V	11.85uA
51	639.6mV	115.9V	12.53uA	628.5mV	118.8V	12.70uA
52	633.0mV	117.4V	12.40uA	628.3mV	116.3V	13.33uA
53	639.3mV	118.5V	13.89uA	634.6mV	118.6V	14.78uA
54	636.3mV	118.2V	12.67uA	638.6mV	115.3V	14.57uA
55	636.2mV	117.0V	13.05uA	638.4mV	115.9V	12.45uA
56	634.9mV	118.4V	10.75uA	635.5mV	116.3V	11.20uA
57	638.4mV	115.6V	14.47uA	635.1mV	117.7V	13.68uA
58	630.8mV	115.4V	11.35uA	636.2mV	117.0V	14.91uA
59	631.7mV	118.3V	13.83uA	626.4mV	116.5V	11.35uA
60	631.2mV	117.8V	14.60uA	628.7mV	117.8V	13.20uA

High Temperature High Humidity Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2018.02.26 ~ 2018.04.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	633.9mV	117.1V	11.06uA	634.5mV	118.7V	13.40uA
62	633.9mV	118.8V	11.94uA	628.4mV	117.9V	13.95uA
63	638.7mV	115.8V	12.45uA	632.0mV	115.8V	11.45uA
64	636.9mV	115.8V	15.07uA	626.6mV	117.0V	13.81uA
65	639.3mV	116.0V	14.17uA	638.6mV	117.7V	10.68uA
66	625.3mV	115.9V	12.32uA	638.5mV	116.9V	11.47uA
67	633.8mV	116.3V	11.66uA	638.4mV	117.2V	11.01uA
68	626.3mV	117.5V	10.82uA	627.0mV	117.1V	13.48uA
69	628.9mV	117.8V	12.87uA	635.8mV	116.2V	12.62uA
70	630.6mV	116.2V	12.20uA	630.5mV	117.8V	12.57uA
71	630.3mV	118.8V	14.78uA	635.8mV	115.4V	14.59uA
72	628.1mV	116.2V	12.00uA	629.8mV	117.1V	14.63uA
73	634.2mV	117.4V	13.29uA	628.5mV	117.4V	13.40uA
74	634.8mV	116.2V	12.21uA	627.5mV	118.7V	12.65uA
75	633.0mV	115.5V	11.54uA	635.7mV	118.0V	12.06uA
76	629.2mV	118.6V	11.87uA	632.7mV	117.9V	11.78uA
77	639.0mV	115.9V	11.35uA	626.3mV	116.9V	11.51uA

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2018.02.27 ~ 2018.04.12
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	639.5mV	118.6V	13.19uA	626.2mV	115.4V	12.76uA
2	633.3mV	118.1V	11.04uA	634.1mV	118.4V	15.10uA
3	627.3mV	115.5V	13.75uA	633.2mV	117.5V	13.90uA
4	630.3mV	117.1V	12.91uA	626.3mV	118.5V	13.14uA
5	633.1mV	117.2V	12.62uA	636.1mV	118.8V	12.14uA
6	633.7mV	116.7V	14.63uA	631.1mV	116.5V	12.03uA
7	626.9mV	116.8V	14.53uA	625.9mV	117.3V	13.41uA
8	625.2mV	118.5V	10.67uA	633.7mV	116.4V	11.10uA
9	631.5mV	116.5V	13.17uA	626.5mV	115.9V	11.71uA
10	631.8mV	116.0V	10.92uA	630.5mV	117.6V	12.63uA
11	628.7mV	115.4V	12.16uA	633.6mV	116.5V	13.96uA
12	638.3mV	115.8V	12.68uA	631.6mV	116.6V	12.50uA
13	629.4mV	116.3V	14.24uA	636.8mV	115.6V	13.91uA
14	632.9mV	117.5V	11.80uA	634.9mV	118.5V	12.12uA
15	629.5mV	115.8V	11.59uA	633.1mV	117.0V	10.76uA
16	636.2mV	116.2V	12.58uA	639.5mV	115.4V	13.68uA
17	636.9mV	116.9V	12.60uA	629.1mV	115.9V	10.72uA
18	627.1mV	116.3V	10.75uA	633.0mV	115.3V	13.42uA
19	631.7mV	115.6V	10.80uA	636.5mV	117.9V	10.69uA
20	630.4mV	116.6V	13.34uA	634.0mV	117.8V	13.33uA
21	639.9mV	118.4V	13.16uA	638.0mV	118.3V	14.03uA
22	635.1mV	115.5V	10.94uA	626.2mV	118.0V	14.96uA
23	634.3mV	117.7V	14.81uA	631.9mV	117.2V	10.68uA
24	637.1mV	116.7V	11.79uA	627.5mV	116.7V	14.11uA
25	629.3mV	115.7V	14.28uA	638.2mV	118.4V	14.93uA
26	627.4mV	115.5V	13.18uA	625.2mV	116.8V	13.69uA
27	635.1mV	115.5V	11.61uA	636.7mV	116.4V	12.06uA
28	630.9mV	116.6V	11.43uA	632.6mV	116.3V	12.87uA
29	629.2mV	117.5V	14.27uA	628.8mV	118.2V	14.73uA
30	630.6mV	118.0V	10.72uA	639.1mV	116.5V	15.16uA

High Temper High Humidity Reverse Bies Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2018.02.27 ~ 2018.04.12
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	634.0mV	115.4V	11.99uA	637.9mV	116.5V	14.10uA
32	627.0mV	118.5V	11.75uA	626.6mV	117.1V	15.02uA
33	634.1mV	117.1V	14.75uA	625.8mV	115.7V	14.33uA
34	634.0mV	118.3V	14.35uA	634.5mV	115.6V	14.44uA
35	630.2mV	115.7V	15.26uA	630.6mV	116.0V	14.39uA
36	627.2mV	117.8V	11.25uA	629.8mV	116.4V	12.89uA
37	625.5mV	118.1V	11.35uA	626.8mV	117.3V	11.12uA
38	631.8mV	116.8V	12.32uA	628.1mV	116.4V	11.55uA
39	625.0mV	116.6V	11.15uA	631.0mV	117.1V	14.85uA
40	631.7mV	116.9V	11.86uA	626.4mV	117.5V	15.13uA
41	635.9mV	117.1V	14.72uA	633.3mV	117.8V	11.67uA
42	634.5mV	116.2V	10.94uA	633.1mV	118.7V	10.90uA
43	629.6mV	118.2V	13.37uA	637.6mV	115.2V	12.14uA
44	629.2mV	115.3V	12.47uA	633.3mV	115.8V	14.33uA
45	628.1mV	115.5V	11.79uA	628.7mV	116.6V	14.01uA
46	636.7mV	117.3V	13.55uA	625.0mV	118.4V	14.09uA
47	635.8mV	115.6V	10.74uA	638.8mV	116.4V	11.57uA
48	625.8mV	115.2V	13.35uA	635.0mV	117.9V	14.44uA
49	634.7mV	116.0V	11.32uA	625.6mV	117.6V	10.87uA
50	633.3mV	115.9V	14.70uA	630.0mV	117.7V	14.73uA
51	633.1mV	115.9V	13.81uA	628.1mV	116.8V	15.18uA
52	635.4mV	115.4V	11.88uA	631.3mV	115.6V	11.31uA
53	629.9mV	116.6V	13.14uA	626.2mV	116.3V	15.01uA
54	635.7mV	118.5V	14.33uA	629.5mV	116.5V	14.38uA
55	634.7mV	115.3V	13.15uA	630.8mV	116.6V	13.84uA
56	625.4mV	117.2V	12.72uA	634.2mV	118.6V	10.94uA
57	629.7mV	117.4V	13.30uA	634.8mV	117.8V	11.21uA
58	628.1mV	117.4V	11.29uA	631.8mV	116.5V	13.58uA
59	638.2mV	118.0V	13.19uA	626.7mV	117.7V	11.62uA
60	629.0mV	116.7V	12.45uA	634.8mV	117.0V	13.98uA

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2018.02.27 ~ 2018.04.12
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	633.6mV	117.8V	13.06uA	626.6mV	116.0V	13.27uA
62	634.0mV	117.2V	13.33uA	639.0mV	118.2V	11.24uA
63	630.1mV	116.7V	15.27uA	638.1mV	118.4V	15.21uA
64	632.2mV	118.0V	11.22uA	631.2mV	118.0V	10.88uA
65	626.5mV	116.2V	13.47uA	637.0mV	116.5V	13.47uA
66	626.1mV	116.5V	12.39uA	625.7mV	117.3V	13.73uA
67	637.5mV	118.0V	11.65uA	628.5mV	118.2V	14.95uA
68	631.9mV	116.0V	12.74uA	625.9mV	116.3V	15.13uA
69	633.3mV	117.8V	13.17uA	632.9mV	118.1V	10.86uA
70	630.4mV	118.1V	13.30uA	633.1mV	117.9V	14.36uA
71	631.7mV	117.1V	10.79uA	634.4mV	118.4V	11.11uA
72	639.2mV	118.8V	10.98uA	635.4mV	116.3V	14.72uA
73	637.6mV	116.8V	15.08uA	635.1mV	116.7V	14.32uA
74	629.4mV	116.2V	10.85uA	629.0mV	116.2V	13.47uA
75	639.8mV	118.7V	12.59uA	634.3mV	117.9V	11.01uA
76	633.0mV	116.7V	15.13uA	634.9mV	118.5V	12.68uA
77	631.1mV	115.5V	12.10uA	636.5mV	118.7V	11.66uA

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Resistance to Solder Heat Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 270℃ ± 5℃, 7Sec + 2Sec/-0Sec
Test Date: 2018.04.13
Test Standard : JESD22 STANDARD Method-B106
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
1	631.3mV	115.6V	14.30uA	628.6mV	116.6V	13.80uA
2	635.4mV	117.4V	11.26uA	635.7mV	116.1V	14.79uA
3	628.8mV	116.3V	12.39uA	629.1mV	118.7V	10.79uA
4	626.4mV	117.1V	13.28uA	639.4mV	118.0V	15.09uA
5	638.7mV	117.5V	12.18uA	639.7mV	117.8V	11.92uA
6	638.3mV	117.8V	11.84uA	639.8mV	116.7V	15.25uA
7	636.5mV	118.7V	11.86uA	625.5mV	115.4V	14.72uA
8	639.0mV	116.6V	13.53uA	635.7mV	116.5V	11.60uA
9	629.7mV	116.5V	11.08uA	629.1mV	115.4V	14.49uA
10	637.9mV	117.5V	14.39uA	633.2mV	115.8V	12.88uA
11	635.7mV	117.3V	14.99uA	626.1mV	115.6V	13.13uA
12	637.0mV	117.4V	13.61uA	632.8mV	118.5V	14.07uA
13	628.5mV	117.7V	13.57uA	633.2mV	118.4V	14.09uA
14	636.0mV	118.7V	11.18uA	638.1mV	117.5V	11.65uA
15	631.9mV	117.6V	12.20uA	625.8mV	116.1V	13.72uA
16	625.8mV	116.2V	13.83uA	633.8mV	118.4V	15.10uA
17	637.3mV	117.8V	13.75uA	635.6mV	115.9V	14.16uA
18	632.5mV	115.3V	14.55uA	627.3mV	115.5V	11.57uA
19	638.1mV	115.4V	12.46uA	633.9mV	116.7V	13.36uA
20	626.5mV	117.6V	14.94uA	633.9mV	117.7V	12.53uA
21	633.6mV	117.2V	11.94uA	638.0mV	115.4V	12.79uA
22	635.2mV	116.3V	13.73uA	634.5mV	117.0V	12.77uA
23	628.3mV	118.3V	11.85uA	626.0mV	115.8V	10.78uA
24	636.4mV	117.2V	14.12uA	637.8mV	118.0V	14.00uA
25	633.2mV	117.9V	12.32uA	635.8mV	117.8V	14.06uA
26	635.6mV	118.1V	13.81uA	633.8mV	116.1V	14.48uA
27	637.9mV	117.7V	14.78uA	628.9mV	115.5V	13.06uA
28	628.4mV	117.0V	14.17uA	638.6mV	115.3V	13.34uA
29	636.9mV	115.7V	14.15uA	635.8mV	118.6V	13.41uA
30	632.6mV	118.5V	11.12uA	627.6mV	115.5V	15.17uA

Resistance to Solder Heat Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 270℃ ± 5℃, 7Sec + 2Sec/-0Sec
Test Date: 2018.04.13
Test Standard : JESD22 STANDARD Method-B106
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
31	628.0mV	118.8V	12.19uA	633.8mV	117.0V	13.54uA
32	638.3mV	116.3V	10.67uA	628.5mV	115.8V	14.21uA
33	628.2mV	115.6V	12.19uA	627.4mV	115.6V	10.94uA
34	637.7mV	116.3V	14.11uA	639.0mV	117.7V	11.30uA
35	632.7mV	116.0V	14.69uA	637.6mV	116.8V	11.49uA
36	630.3mV	115.7V	15.13uA	627.3mV	118.6V	14.24uA
37	630.1mV	116.4V	11.98uA	639.8mV	115.9V	14.56uA
38	634.6mV	116.7V	14.19uA	634.3mV	116.0V	14.74uA
39	625.3mV	116.1V	14.14uA	626.6mV	115.7V	13.45uA
40	627.8mV	117.3V	14.41uA	631.6mV	118.6V	14.62uA
41	638.4mV	116.6V	13.06uA	625.2mV	118.3V	14.91uA
42	632.7mV	118.3V	14.77uA	626.2mV	115.3V	11.25uA
43	634.9mV	117.0V	12.12uA	633.1mV	116.1V	11.56uA
44	627.9mV	116.2V	12.87uA	631.4mV	115.9V	12.60uA
45	625.7mV	115.8V	12.79uA	625.6mV	118.5V	12.17uA
46	628.5mV	118.6V	12.20uA	636.0mV	117.7V	12.17uA
47	633.9mV	116.8V	14.30uA	634.6mV	116.4V	13.15uA
48	633.7mV	116.6V	12.52uA	632.9mV	115.9V	13.06uA
49	633.6mV	117.3V	12.81uA	638.5mV	117.5V	13.39uA
50	627.2mV	117.6V	14.42uA	631.5mV	115.7V	12.95uA
51	625.0mV	116.1V	14.15uA	629.8mV	117.0V	12.72uA
52	632.3mV	115.9V	12.78uA	629.8mV	116.0V	15.10uA
53	631.6mV	115.7V	12.16uA	635.7mV	117.4V	10.79uA
54	626.8mV	117.0V	11.09uA	632.5mV	118.5V	15.23uA
55	629.0mV	116.5V	11.42uA	632.0mV	118.8V	12.69uA
56	627.6mV	116.0V	14.37uA	628.4mV	117.0V	12.37uA
57	629.2mV	117.3V	12.12uA	628.5mV	116.0V	13.63uA
58	636.2mV	118.4V	12.49uA	627.9mV	116.9V	11.71uA
59	625.1mV	117.6V	10.78uA	638.3mV	116.1V	11.41uA
60	632.0mV	116.5V	15.24uA	632.2mV	118.0V	14.71uA

SeCoS Corporation

Resistance to Solder Heat Test Data

Report No : T180413-B10100L
Part No : SMPB10100L-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<720mV@IF=10A, VB>100V@IR=1mA, IR<100uA@VR=100V
Test Condition: 270℃ ± 5℃, 7Sec + 2Sec/-0Sec
Test Date: 2018.04.13
Test Standard : JESD22 STANDARD Method-B106
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF	VB	IR	VF	VB	IR
61	627.9mV	116.7V	13.58uA	630.5mV	116.6V	11.00uA
62	626.4mV	118.5V	13.97uA	629.2mV	115.7V	14.31uA
63	627.4mV	115.9V	14.77uA	634.7mV	115.4V	10.89uA
64	628.6mV	118.8V	13.68uA	628.9mV	117.6V	14.65uA
65	635.1mV	116.1V	11.46uA	631.7mV	117.4V	11.10uA
66	626.1mV	117.5V	12.65uA	626.7mV	118.4V	15.23uA
67	626.8mV	118.0V	15.03uA	633.7mV	116.7V	11.33uA
68	628.1mV	115.9V	14.78uA	637.2mV	117.8V	15.26uA
69	639.8mV	118.8V	12.53uA	637.1mV	115.2V	13.61uA
70	635.2mV	118.3V	12.23uA	634.6mV	117.7V	12.07uA
71	632.8mV	118.4V	14.83uA	629.8mV	117.5V	14.88uA
72	626.0mV	117.0V	11.62uA	637.3mV	115.5V	11.83uA
73	627.5mV	118.3V	12.28uA	630.5mV	115.8V	13.74uA
74	628.1mV	116.2V	13.36uA	626.4mV	116.7V	10.95uA
75	627.5mV	117.6V	14.60uA	626.0mV	117.5V	13.62uA
76	637.2mV	116.2V	13.46uA	629.9mV	115.2V	11.86uA
77	635.7mV	115.6V	14.78uA	634.1mV	117.6V	12.08uA

Made By: King Huang

Approval: Peter Yang